

# SKiM609GAL12E4 V2



SKiM® 93

## Trench IGBT Modules

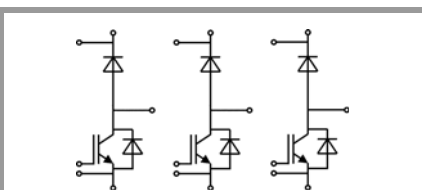
### SKiM609GAL12E4 V2

#### Features\*

- IGBT 4 Trench Gate Technology
- Solderless sinter technology
- $V_{CE(sat)}$  with positive temperature coefficient
- Low inductance case
- Insulated by  $Al_2O_3$  DBC (Direct Bonded Copper) ceramic substrate
- Pressure contact technology for thermal contacts
- Spring contact system to attach driver PCB to the control terminals
- High short circuit capability, self limiting to  $6 \times I_C$
- Integrated temperature sensor

#### Remarks\*

- Case temperature limited to  $T_s = 125^\circ C$  max;  $T_c = T_s$  (for baseplateless modules)
- Recommended  $T_{op} = -40 \dots +150^\circ C$



GAL

Absolute Maximum Ratings				
Symbol	Conditions		Values	Unit
<b>IGBT</b>				
$V_{CES}$	$T_j = 25^\circ C$		1200	V
$I_C$	$\lambda_{paste}=0.8 \text{ W/(mK)}$	$T_s = 25^\circ C$	748	A
		$T_j = 175^\circ C$	608	A
$I_C$	$\lambda_{paste}=2.5 \text{ W/(mK)}$	$T_s = 25^\circ C$	845	A
		$T_j = 175^\circ C$	688	A
$I_{Chom}$			600	A
$I_{CRM}$			1800	A
$V_{GES}$			-20 ... 20	V
$t_{psc}$	$V_{CC} = 800 \text{ V}, V_{GE} \leq 15 \text{ V}, T_j = 150^\circ C,$ $V_{CES} \leq 1200 \text{ V}$		10	$\mu s$
$T_j$			-40 ... 175	$^\circ C$
<b>Inverse diode</b>				
$V_{RRM}$	$T_j = 25^\circ C$		1200	V
$I_F$	$\lambda_{paste}=0.8 \text{ W/(mK)}$	$T_s = 25^\circ C$	139	A
		$T_j = 175^\circ C$	110	A
$I_F$	$\lambda_{paste}=2.5 \text{ W/(mK)}$	$T_s = 25^\circ C$	172	A
		$T_j = 175^\circ C$	137	A
$I_{FRM}$			300	A
$I_{FSM}$	10 ms, sin 180°, $T_j = 25^\circ C$		900	A
$T_j$			-40 ... 175	$^\circ C$
<b>Freewheeling diode</b>				
$V_{RRM}$	$T_j = 25^\circ C$		1200	V
$I_F$	$\lambda_{paste}=0.8 \text{ W/(mK)}$	$T_s = 25^\circ C$	1328	A
		$T_j = 175^\circ C$	1052	A
$I_F$	$\lambda_{paste}=2.5 \text{ W/(mK)}$	$T_s = 25^\circ C$	1418	A
		$T_j = 175^\circ C$	1126	A
$I_{FRM}$			1200	A
$I_{FSM}$	10 ms, sin 180°, $T_j = 25^\circ C$		6480	A
$T_j$			-40 ... 175	$^\circ C$
<b>Module</b>				
$I_{t(RMS)}$	$T_{terminal} = 80^\circ C$		700	A
$T_{stg}$			-40 ... 125	$^\circ C$
$V_{isol}$	AC sinus 50 Hz, $t = 1 \text{ min}$		2500	V

Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
<b>IGBT</b>						
$V_{CE(sat)}$	$I_C = 600 \text{ A}$ $V_{GE} = 15 \text{ V}$ chipllevel	$T_j = 25^\circ C$	1.85	2.10		V
		$T_j = 150^\circ C$	2.25	2.45		V
$V_{CE0}$	chipllevel	$T_j = 25^\circ C$	0.80	0.90		V
		$T_j = 150^\circ C$	0.70	0.80		V
$r_{CE}$	$V_{GE} = 15 \text{ V}$ chipllevel	$T_j = 25^\circ C$	1.75	2.0		m $\Omega$
		$T_j = 150^\circ C$	2.6	2.8		m $\Omega$
$V_{GE(th)}$	$V_{GE} = V_{CE}, I_C = 24 \text{ mA}$		5	5.8	6.5	V
$I_{CES}$	$V_{GE} = 0 \text{ V}, V_{CE} = 1200 \text{ V}, T_j = 25^\circ C$		0.1	5		mA
$C_{ies}$	$V_{CE} = 25 \text{ V}$ $V_{GE} = 0 \text{ V}$	$f = 1 \text{ MHz}$	35.2			nF
$C_{oes}$		$f = 1 \text{ MHz}$	2.32			nF
$C_{res}$		$f = 1 \text{ MHz}$	1.88			nF
$Q_G$	$V_{GE} = -8 \text{ V} \dots +15 \text{ V}$		3400			nC

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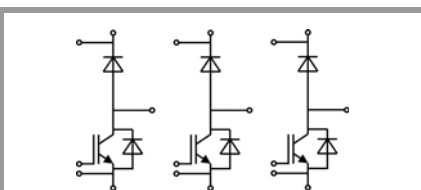
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Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
<b>IGBT</b>						
$R_{Gint}$	$T_j = 25^\circ C$			1.3		$\Omega$
$t_{d(on)}$	$V_{CC} = 600 V$	$T_j = 150^\circ C$		150		ns
$t_r$	$I_C = 600 A$	$T_j = 150^\circ C$		121		ns
$E_{on}$	$V_{GE} = +15/-15 V$	$T_j = 150^\circ C$		136		mJ
$t_{d(off)}$	$R_{G on} = 4.1 \Omega$	$T_j = 150^\circ C$		808		ns
$t_f$	$R_{G off} = 4.1 \Omega$	$T_j = 150^\circ C$		100		ns
$E_{off}$	$di/dt_{on} = 5000 A/\mu s$ $di/dt_{off} = 4400 A/\mu s$	$T_j = 150^\circ C$		83		mJ
$R_{th(j-s)}$	per IGBT, $\lambda_{paste}=0.8 W/(mK)$			0.068		K/W
$R_{th(j-s)}$	per IGBT, $\lambda_{paste}=2.5 W/(mK)$			0.055		K/W
<b>Inverse diode</b>						
$V_F = V_{EC}$	$I_F = 150 A$	$T_j = 25^\circ C$		2.14	2.46	V
	chipelevel	$T_j = 150^\circ C$		2.07	2.38	V
$V_{F0}$	$I_F = 150 A$	$T_j = 25^\circ C$		1.30	1.50	V
	chipelevel	$T_j = 150^\circ C$		0.90	1.10	V
$r_F$	$I_F = 150 A$	$T_j = 25^\circ C$		5.6	6.4	m $\Omega$
	chipelevel	$T_j = 150^\circ C$		7.8	8.5	m $\Omega$
$I_{RRM}$	$I_F = 150 A$	$T_j = 150^\circ C$		153		A
$Q_{rr}$	$di/dt_{off} = 3300 A/\mu s$	$T_j = 150^\circ C$		15		$\mu C$
$E_{rr}$	$V_R = 600 V$ $V_{GE} = +15/-15 V$	$T_j = 150^\circ C$		9		mJ
$R_{th(j-s)}$	per Diode, $\lambda_{paste}=0.8 W/(mK)$			0.501		K/W
$R_{th(j-s)}$	per Diode, $\lambda_{paste}=2.5 W/(mK)$			0.361		K/W
<b>Freewheeling diode</b>						
$V_F = V_{EC}$	$I_F = 600 A$	$T_j = 25^\circ C$		1.67	1.93	V
	chipelevel	$T_j = 150^\circ C$		1.42	1.67	V
$V_{F0}$	$I_F = 600 A$	$T_j = 25^\circ C$		1.30	1.50	V
	chipelevel	$T_j = 150^\circ C$		0.90	1.10	V
$r_F$	$I_F = 600 A$	$T_j = 25^\circ C$		0.62	0.71	m $\Omega$
	chipelevel	$T_j = 150^\circ C$		0.87	0.95	m $\Omega$
$I_{RRM}$	$I_F = 600 A$	$T_j = 150^\circ C$		510		A
$Q_{rr}$	$di/dt_{off} = 5300 A/\mu s$	$T_j = 150^\circ C$		123		$\mu C$
$E_{rr} \text{ } ^1)$	$V_R = 600 V$ $V_{GE} = +/-15 V$	$T_j = 150^\circ C$		39		mJ
$R_{th(j-s)}$	per Diode, $\lambda_{paste}=0.8 W/(mK)$			0.051		K/W
$R_{th(j-s)}$	per Diode, $\lambda_{paste}=2.5 W/(mK)$			0.046		K/W

Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
<b>Temperature Sensor</b>						
$R_{100}$	$T_r=100^\circ C$ ( $R_{25}=1000\Omega$ )			1670 $\pm$ 1%		$\Omega$
$R_{(T)}$	$R(T)=1k\Omega[1+A(T-25^\circ C)+B(T-25^\circ C)^2]$ , $A = 7.64 \cdot 10^{-3} C^{-1}$ , $B = 1.73 \cdot 10^{-5} C^{-2}$					

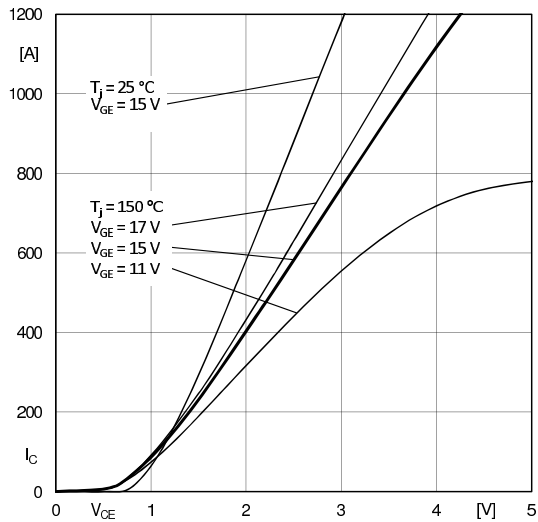


Fig. 1: Typ. output characteristic, inclusive  $R_{CC'+EE'}$

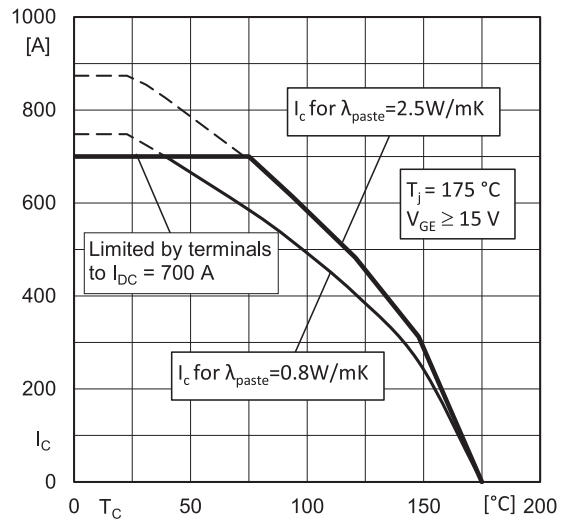


Fig. 2: Typ. rated current vs. temperature  $I_C = f(T_S)$

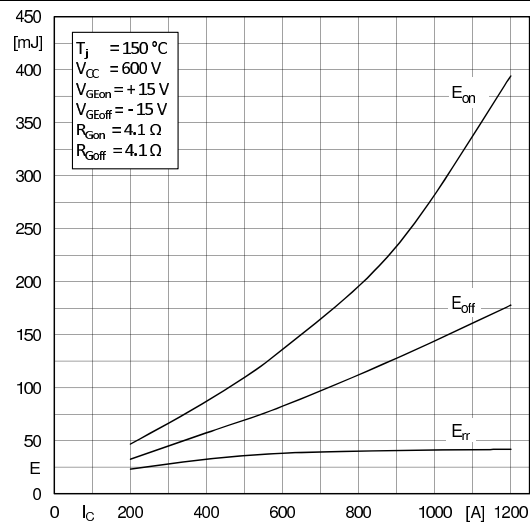


Fig. 3: Typ. turn-on /-off energy =  $f(I_C)$

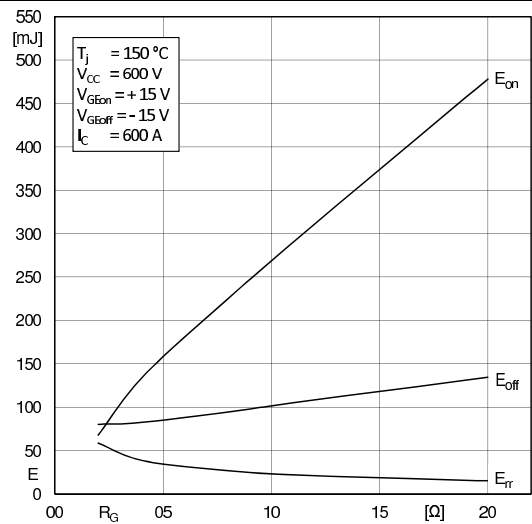


Fig. 4: Typ. turn-on /-off energy =  $f(R_G)$

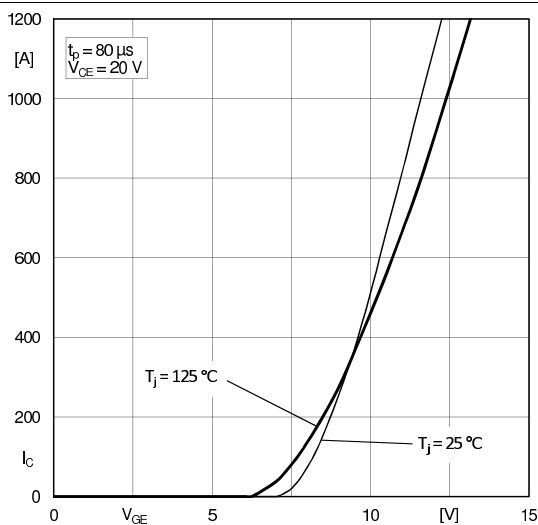


Fig. 5: Typ. transfer characteristic

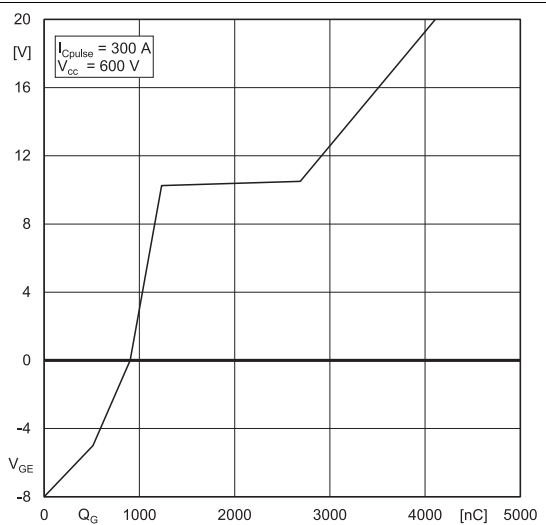


Fig. 6: Typ. gate charge characteristic

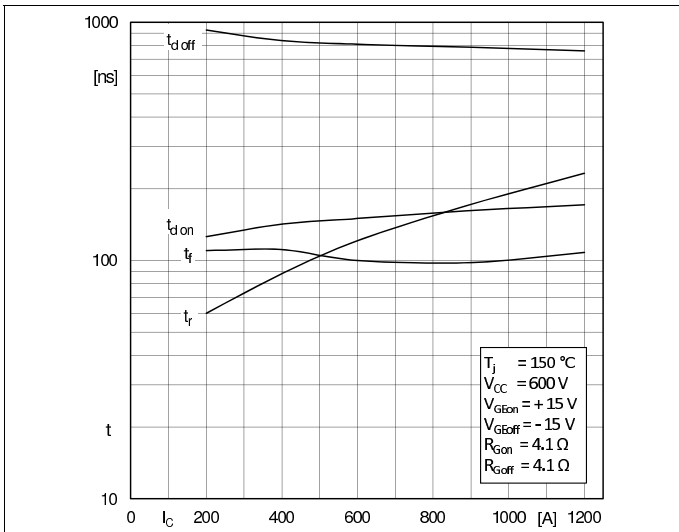


Fig. 7: Typ. switching times vs.  $I_c$

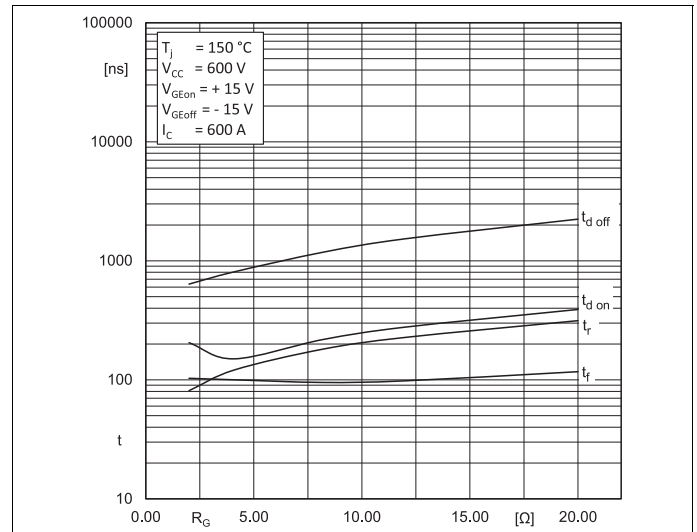


Fig. 8: Typ. switching times vs. gate resistor  $R_G$

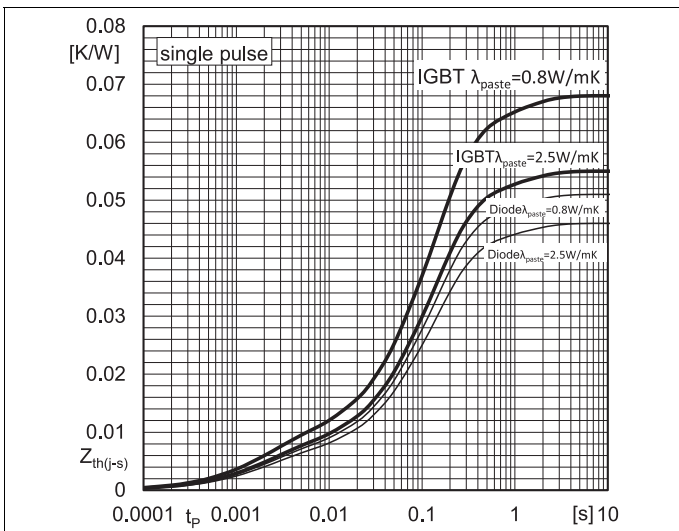


Fig. 9: Typ. transient thermal impedance

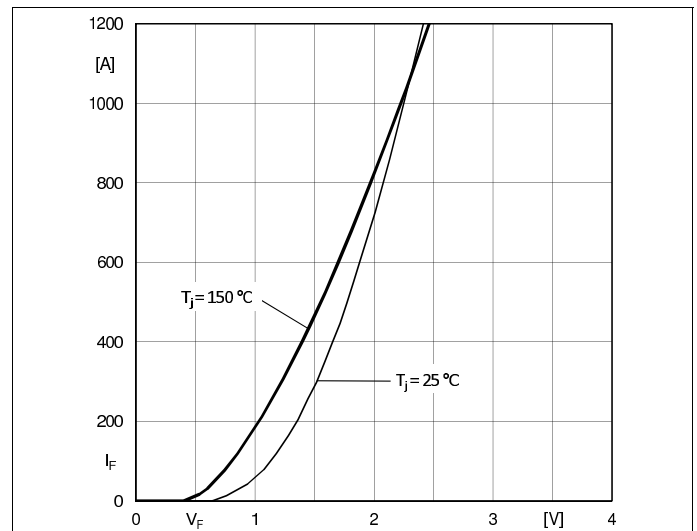


Fig. 10: Typ. CAL diode forward charact., incl.  $R_{CC+EE'}$

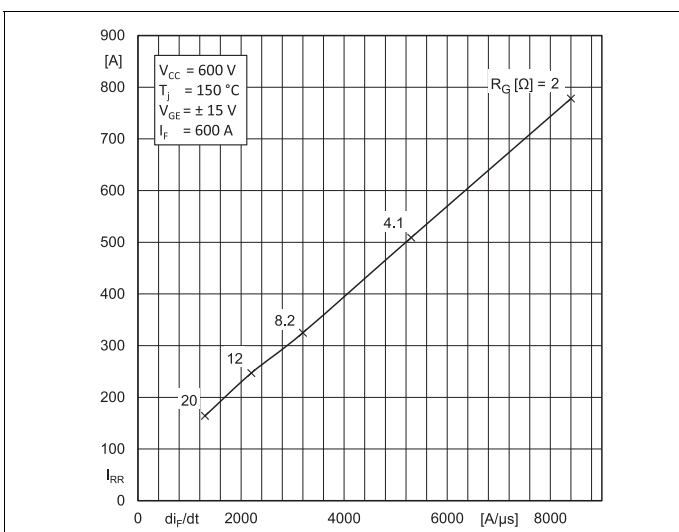


Fig. 11: Typ. CAL diode peak reverse recovery current

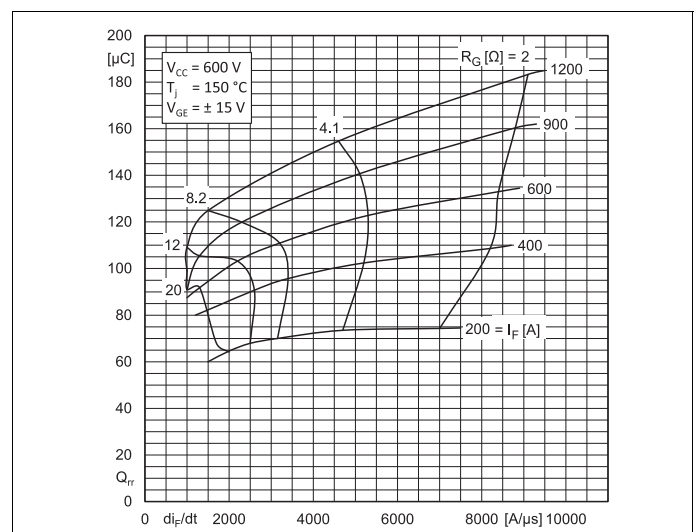
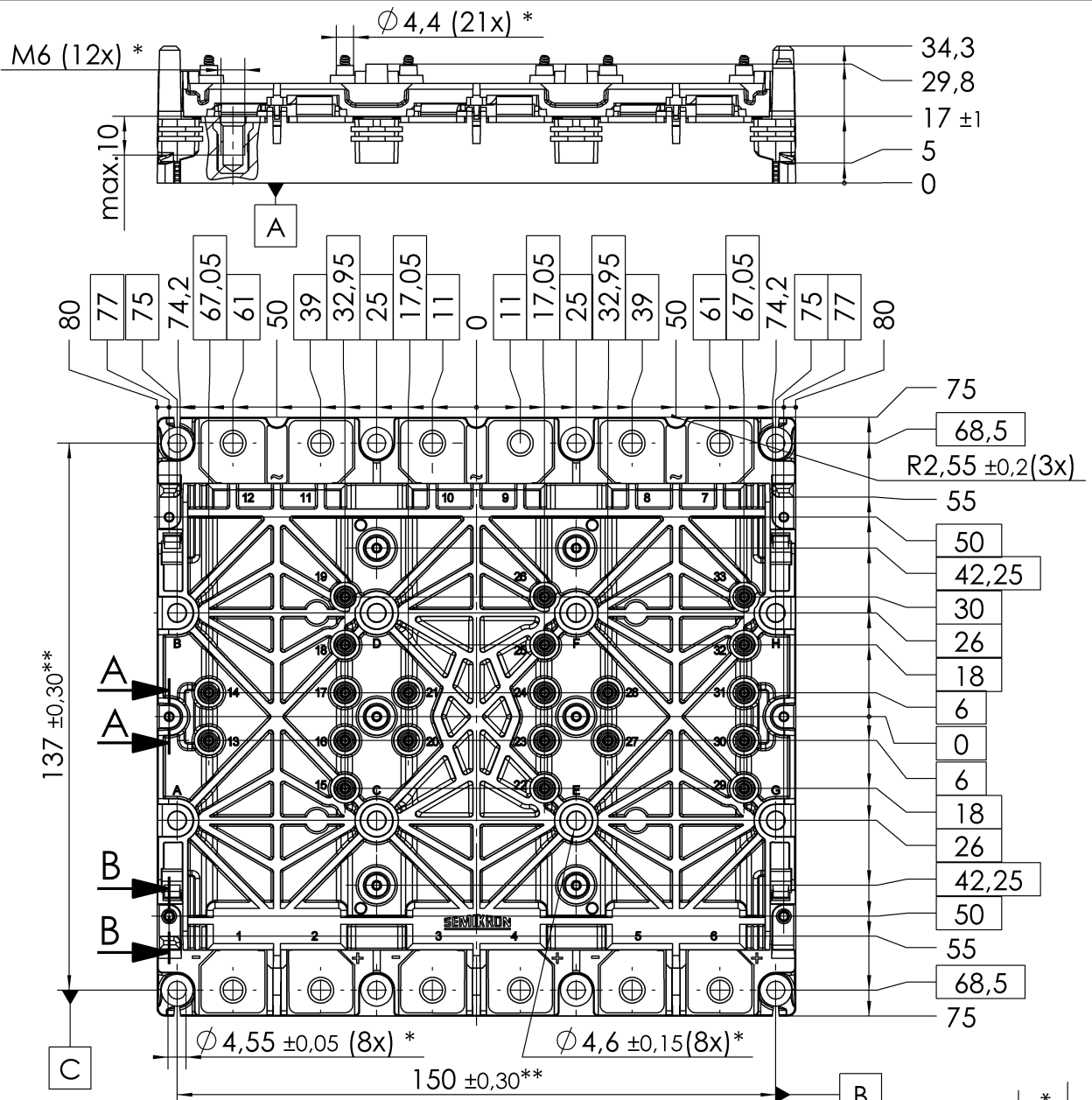
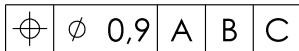


Fig. 12: Typ. CAL diode recovery charge

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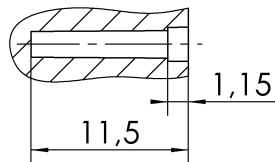
\* all pos. dimensions valid when mounted



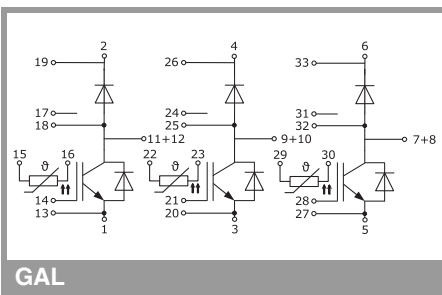
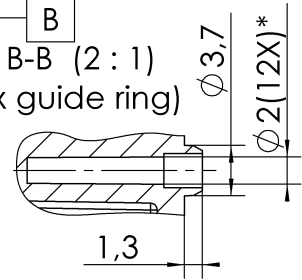
\*\* valid for the outer 4 inserts

General Tolerances DIN ISO 2768-m  
PCB spring landing pad =  $\varnothing 3,5 \pm 0,2$

A-A (2:1)  
(12x screw hole)



B-B (2:1)  
(2x guide ring)



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This is an electrostatic discharge sensitive device (ESDS) due to international standard IEC 61340.

## **\*IMPORTANT INFORMATION AND WARNINGS**

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